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Elsayed-Ali et al. 1991

lostetler et al. 1999. Groeneveld et al. 199

# LIGHT INDUCED ULTRAFAST THERMAL PROCESSES IN METAL: THERMAL **EVOLUTION TO MATERIAL DAMAGE**

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# Introduction

## Motivation

- □ Micro-machining of thin 3D materials or 2D materials with ultrafast laser pulses is currently active area of research.
- Availability of accurate models of material processing provides theoretical understanding of experimental parameters and informs avenues of future development.



# **Description of Model – Source Term**

### **Gaussian Beam**

- Full Gaussian beam formalism used to find incident energy on material surface.
- **7** beam parameters: intensity, waist size, wavelength, angle of incidence, beam divergence, polarization, and pulse duration



# **Description of Model – Thermal Properties** C<sub>o</sub>(T<sub>o</sub>) with Au DOS - $C_e(T_e) = \gamma_{exp}T_e$ , $\gamma_{exp} = 67.6 \text{ Jm}^{-3}\text{K}^{-2}$ $-\cdot - \cdot - C_a(T_a) = \gamma_{th}T_a, \gamma_{th} = 62.9 \text{ Jm}^{-3}\text{K}$

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□ Model discussed here analyzes the effects of micro-machining materials from an oblique angle, which can be used for fluence control and creation of oblong damage craters.

## Theory

- □ The two-temperature model (TTM) assumes thermal energy in a material is made up of electron temperature and lattice or phonon temperature.
- TTM has been successful in describing pico- and femto-second processes in which electron and lattice temperatures are coupled but not equal, such as ultrafast laser damage.

 $C_e \partial_t T_e = \nabla \cdot \left[ k_e \nabla T_e \right] - G(T_e - T_l) + Q$  $C_l \partial_t T_l = \nabla \cdot \left[ k_l \nabla T_e \right] + G(T_e - T_l)$ 



Results

20 µm

20 µm







□ Simulation shows good agreement with experimental results. Absorption only model, which accounts for only threshold changes due to increased spot size and Fresnel reflection, is responsible for most of the threshold dependence on angle.

Combined effect of increased spot size and Fresnel reflection reduces deposited energy dramatically for higher angles, in the S-polarized case

### References

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